

Notice of References Cited	Application/Control No. 10/789,682	Applicant(s)/Patent Under Reexamination WAN ET AL.	
	Examiner Kenneth J. Whittington	Art Unit 2862	Page 1 of 1

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	B	US-2005/0017714 A1	01-2005	Beichler et al.	324/247
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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